Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1340	706/12,16,21,23-25.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 12:52
L2	15717	700/57,121,160;250/492.2,492. 22,492.3;355/53,55,77;430/5,296, 942;716/19,21.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 12:55
L3	4832	700/57,121,160;250/492.2,492.	US-PGPUB;	OR	OFF	2005/03/01 12:55
		22,492.3.ccls.	USPAT; EPO; JPO;			
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		and the state of t	IBM_TDB	i i i.		\$
L4	9813	700/57,121,160;250/492.2,492. 22,492.3;355/53,55,77.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 13:40
L5	6630	430/5,296,942;716/19,21.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 13:41
L6	5904	5 not 4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:28
L7	3	"6707941".pn.	US-PGPUB; USPAT; EPO; JPO;	OR	OFF	2005/03/01 14:29
			DERWENT; IBM_TDB		i : :	
L8	2	"6002484".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:29
L9	88	(electron adj beam or e-beam) with exposure adj dose with pattern	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:40

L10	5	(electron adj beam or e-beam) with (smear\$4 adj function or blur\$4 adj function)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:42
L11	252	(electron adj beam or e-beam) with exposure adj dose	US-PGPUB; USPAT; EPO; JPO;	OR	OFF	2005/03/01 14:42
-3			DERWENT; IBM_TDB			
L12	95	(electron adj beam or e-beam) near (smear\$4 or blur\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:47
L13	24	(pec or proximity adj effect adj compensation) with electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:49
L14	636	(proximity near effect) with (electron adj beam or e-beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:49
L15	2	exposure adj doses with ((positive or negative) adj values)	US-PGPUB; USPAT;	OR	OFF	2005/03/01 14:58
		or negative) auj values)	EPO; JPO; DERWENT; IBM_TDB			
L16	5	(smear\$4 adj function or blur\$4 adj function) with (electron adj beam or e-beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:59
L17	1	smearing adj matrix with inverse	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 14:59
L18	1	(smearing adj function or blur adj function) with (pattern adj point)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 15:00
L19	7	(electron adj beam or e-beam) with (pattern adj point)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR -	OFF	2005/03/01 15:00

L20	3	pattern with (smearing adj function)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 15:00
L21	153	(smearing adj function or blur adj function)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 15:01
L22	20	(dose near prediction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 15:05
L23	20	(dose near prediction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 15:05
L24	1	(electron adj beam or e-beam) with lithography with (smear\$4 adj function or blur\$4 adj function)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/01 15:06